

Fault diagnosis in integrated circuits with BIST

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan; Evartson, Teet; Lensen, Harri 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 604-610 : ill <http://dx.doi.org/10.1109/DSD.2007.4341530>

Hierarchical identification of untestable faults in sequential circuits

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Hybrid BIST optimization using reseeding and test set compaction

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